## 2-Propanol CMOS

(iso-propyl alcohol)





Material No.: 9079-05 Batch No.: 0000060045

Manufactured Date: 2013/09/29

Retest Date: 2018/09/28

## Certificate of Analysis

Test	Specification	Result
Assay (CH <sub>3</sub> CHOHCH <sub>3</sub> )	>= 99.5 %	100.0
Color (APHA)	<= 10	5
Residue after Evaporation	<= 4 ppm	< 1
Solubility in H <sub>2</sub> O	Passes Test	PT
Water (H2O)(by Karl Fischer titrn)	<= 0.05 %	0.01
Acidity (µeq/g)	<= 0.2	0.1
Alkalinity (µeq/g)	<= 0.1	< 0.1
Chloride (CI)	<= 0.1 ppm	< 0.1
Phosphate (PO <sub>4</sub> )	<= 0.3 ppm	< 0.3
Trace Impurities - Aluminum (Al)	<= 50.0 ppb	< 5.0
Arsenic and Antimony (as As)	<= 10 ppb	< 10
Trace Impurities - Barium (Ba)	<= 20.0 ppb	< 1.0
Trace Impurities - Beryllium (Be)	<= 100.0 ppb	< 1.0
Trace Impurities - Bismuth (Bi)	<= 100.0 ppb	< 10.0
Trace Impurities - Boron (B)	<= 10.0 ppb	< 5.0
Trace Impurities - Cadmium (Cd)	<= 20.0 ppb	< 1.0
Trace Impurities - Calcium (Ca)	<= 50.0 ppb	2.7
Trace Impurities - Chromium (Cr)	<= 20.0 ppb	< 1.0
Trace Impurities - Cobalt (Co)	<= 20.0 ppb	< 1.0
Trace Impurities – Copper (Cu)	<= 10.0 ppb	< 1.0
Trace Impurities - Gallium (Ga)	<= 50.0 ppb	< 1.0
Trace Impurities - Germanium (Ge)	<= 50.0 ppb	< 10.0
Trace Impurities - Gold (Au)	<= 20.0 ppb	< 5.0
Heavy Metals (as Pb)	<= 200 ppb	< 100

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Trace Impurities – Iron (Fe)	<= 50.0 ppb	< 1.0
Trace Impurities – Lead (Pb)	<= 20.0 ppb	< 10.0
Trace Impurities – Lithium (Li)	<= 50.0 ppb	< 1.0
Trace Impurities – Magnesium (Mg)	<= 20.0 ppb	< 1.0
Trace Impurities – Manganese (Mn)	<= 15.0 ppb	< 1.0
Trace Impurities – Molybdenum (Mo)	<= 100.0 ppb	< 5.0
Trace Impurities – Nickel (Ni)	<= 10.0 ppb	< 5.0
Trace Impurities – Niobium (Nb)	<= 100.0 ppb	< 1.0
Trace Impurities – Potassium (K)	<= 100.0 ppb	< 10.0
Trace Impurities – Silicon (Si)	<= 50.0 ppb	< 10.0
Trace Impurities – Silver (Ag)	<= 20.0 ppb	< 1.0
Trace Impurities – Sodium (Na)	<= 100.0 ppb	< 5.0
Trace Impurities – Strontium (Sr)	<= 20.0 ppb	< 1.0
Trace Impurities – Tantalum (Ta)	<= 100.0 ppb	< 5.0
Trace Impurities – Thallium (Tl)	<= 10.0 ppb	< 5.0
Trace Impurities - Tin (Sn)	<= 100.0 ppb	< 10.0
Trace Impurities – Titanium (Ti)	<= 20.0 ppb	< 1.0
Trace Impurities - Vanadium (V)	<= 100.0 ppb	< 1.0
Trace Impurities - Zinc (Zn)	<= 50.0 ppb	< 1.0
Trace Impurities – Zirconium (Zr)	<= 100.0 ppb	< 1.0
Particle Count – 0.2 µm and greater	<= 5000 par/ml	108
Particle Count – 0.3 µm and greater	<= 5000 par/ml	20
Particle Count – 0.5 µm and greater	<= 50 par/ml	8
Particle Count – 1.0 µm and greater	<= 8 par/ml	2

For Microelectronic Use

Country of Origin: US

Packaging Site: Paris Mfg Ctr & DC



Phillipsburg, NJ 9001:2008, 14001:2004
Paris, KY 9001:2008
Mexico City, Mexico 9001:2008
Deventer, The Netherlands 9001:2008, 14001:2004, 13485:2003
Gliwice, Poland 9001:2008, 17025:2005
Selangor, Malaysia 9001:2008
Dehradun, India, 9001:2008, 14001:2004, 13485:2003
Mumbai, India, 9001:2008, 17025:2005
Panoli, India 9001:2008

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